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(Release 10)

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Contents

Intellectual Property Rights 11
Foreword 11
Modal verbs terminology 11
Introduction 11
1 Scope 12
2 References 12
2.1 Normative references 12
2.2 Informative references 13
3 Definitions, symbols and abbreviations 13
3.1 Definitions 13
3.2 Symbols 14
3.3 Abbreviations 14
3.4 Formats 15
3.4.1 Format of the table of optional features 15
3.4.2 Format of the applicability table 15
3.4.3 Status and Notations 15
4 Test environment 16
4.1 Table of optional features 16
4.2 Applicability table 17
4.3 Information to be provided by the DUT supplier 22
4.4 Test equipment 22
4.4.1 Measurement/setting uncertainties 22
4.4.2 Default conditions for DUT operation 23
4.4.2.1 Temperature 23
4.4.2.2 ETSI TS 102 221 interface contacts (CLK, RST, I/O) and contact Vcc 24
4.4.2.3 ETSI TS 102 600 interface contacts (IC_DP, IC_DM) 24
4.4.2.4 ETSI TS 102 613 interface contact (SWIO) 25
4.4.2.5 Status of UICC interfaces 25
4.4.2.6 Characteristics of LLC's 25
4.4.2.6.1 ACT LLC 25
4.4.2.6.2 SHDLC LLC 25
4.4.2.6.3 CLT LLC 26
4.4.3 Minimum/maximum conditions for DUT operation 26
4.4.3.1 Temperature 26
4.4.3.2 Contact Vcc 26
4.5 Test execution 26
4.5.1 Parameter variations 26
4.5.2 Execution requirements 26
4.6 Pass criterion 27
5 Test cases 27
5.1 Principle of the Single Wire Protocol 27
5.2 System architecture 27
5.2.1 General overview 27
5.2.2 ETSI TS 102 221 support 27
5.2.2.1 Conformance requirements 27
5.2.3 Configurations 28
5.2.3.1 Conformance requirements 28
5.2.3.2 Test case 1: Global Interface bytes of the ATR 28
5.2.3.2.1 Test execution 28
5.2.3.2.2 Initial conditions 28
5.2.3.2.3 Test procedure 28
5.2.3.3 Test case 2: interaction with ETSI TS 102 221 interface - SWP activation while the UICC receives data 28
5.2.3.3.1 Test execution 28

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5.2.3.3.2 Initial conditions 28
5.2.3.3.3 Test procedure 29
5.2.3.4 Test case 3: interaction with ETSI TS 102 221 interface - SWP activation while the UICC sends data 29
5.2.3.4.1 Test execution 29
5.2.3.4.2 Initial conditions 29
5.2.3.4.3 Test procedure 29
5.2.4 Interaction with other interfaces 30
5.2.4.1 Conformance requirements 30
5.2.4.2 Test case 1: interaction with ETSI TS 102 221 interface - ETSI TS 102 221 clock stop 30
5.2.4.2.1 Test execution 30
5.2.4.2.2 Initial conditions 30
5.2.4.2.3 Test procedure 30
5.2.4.3 Test case 2: interaction with ETSI TS 102 221 interface - ETSI TS 102 221 reset 30
5.2.4.3.1 Test execution 30
5.2.4.3.2 Initial conditions 30
5.2.4.3.3 Test procedure 31
5.2.4.4 Test case 3: interaction with ETSI TS 102 221 interface - SWP deactivation while the UICC receives data 31
5.2.4.4.1 Test execution 31
5.2.4.4.2 Initial conditions 31
5.2.4.4.3 Test procedure 31
5.2.4.5 Test case 4: interaction with ETSI TS 102 221 interface - SWP deactivation while the UICC sends data 31
5.2.4.5.1 Test execution 31
5.2.4.5.2 Initial conditions 32
5.2.4.5.3 Test procedure 32
5.2.4.6 Test case 5: interaction with ETSI TS 102 221 interface - reset SWP while the UICC receives data 32
5.2.4.6.1 Test execution 32
5.2.4.6.2 Initial conditions 32
5.2.4.6.3 Test procedure 32
5.2.4.7 Test case 6: interaction with ETSI TS 102 221 interface - reset SWP while the UICC sends data 33
5.2.4.7.1 Test execution 33
5.2.4.7.2 Initial conditions 33
5.2.4.7.3 Test procedure 33
5.2.4.8 Test case 7: interaction with ETSI TS 102 221 interface - activate SWP in ETSI TS 102 221 clock stop 33
5.2.4.8.1 Test execution 33
5.2.4.8.2 Initial conditions 33
5.2.4.8.3 Test procedure 33
5.3 Physical characteristics 34
5.3.1 Temperature range for card operations 34
5.3.1.1 Conformance requirements 34
5.3.2 Contacts 34
5.3.2.1 Provision of contacts 34
5.3.2.1.1 Conformance requirements 34
5.3.2.2 Contact activation and deactivation 34
5.3.2.2.1 Conformance requirements 34
5.3.2.3 Interface activation 34
5.3.2.3.1 Conformance requirements 34
5.3.2.3.2 Test case 1: initial activation in low power mode 35
5.3.2.3.3 Test case 2: initial activation in low power mode with corrupted frames 36
5.3.2.3.4 Test case 3: no activation 36
5.3.2.3.5 Void 37
5.3.2.3.6 Test case 5: full power mode activation 37
5.3.2.3.7 Test case 6: low power mode activation with re-transmission of ACT_SYNC 37
5.3.2.3.8 Test case 7: full power mode activation with re-transmission of ACT_SYNC 38
5.3.2.3.9 Void 38
5.3.2.3.10 Test case 9: low power mode activation with multiple re-transmission of ACT_SYNC 38
5.3.2.3.11 Test case 10: full power mode activation with re-transmission of ACT_READY 39
5.3.2.3.12 Test case 11: full power mode activation with multiple re-transmission of ACT_SYNC 39

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5.3.2.3.13 Test case 12: subsequent activation in low power mode 40
5.3.2.3.14 Test case 13: subsequent activation in full power mode 40
5.3.2.3.15 Void 41
5.3.2.4 Behaviour of a UICC in a terminal not supporting SWP 41
5.3.2.4.1 Conformance requirements 41
5.3.2.4.2 Test case 1: detect terminal not supporting SWP by TERMINAL CAPABILITIES, classes B and C 41
5.3.2.4.3 Test case 2: detect terminal not supporting SWP by TERMINAL CAPABILITIES, class A 41
5.3.2.5 Behaviour of a terminal connected to a UICC not supporting SWP 42
5.3.2.6 Inactive contacts 42
5.4 Electrical characteristics 42
5.4.1 Operating conditions 42
5.4.1.1 Operating conditions 42
5.4.1.2 Supply voltage classes 42
5.4.1.2.1 Conformance requirements 42
5.4.1.2.2 Test case 1: ETSI TS 102 221 voltage classes B and C support 42
5.4.1.3 Vcc (C1) low power mode definition 43
5.4.1.3.1 Conformance requirements 43
5.4.1.3.2 Test case 1: operation in low power mode 43
5.4.1.4 Signal S1 43
5.4.1.4.1 Conformance requirements 43
5.4.1.4.2 Test case 1: S1 communication in voltage class B 44
5.4.1.4.3 Test case 2: S1 communication in voltage class C, full power mode 45
5.4.1.4.4 Test case 3: S1 communication in low power mode 46
5.4.1.5 Signal S2 47
5.4.1.5.1 Signal S2 47
5.4.1.5.2 Operating current for S2 47
5.5 Physical transmission layer 50
5.5.1 S1 Bit coding and sampling time 50
5.5.1.1 Conformance requirements 50
5.5.1.2 Test case 1: communication with timing variation, default bit duration 51
5.5.1.2.1 Test execution 51
5.5.1.2.2 Initial conditions 51
5.5.1.2.3 Test procedure 51
5.5.1.3 Test case 2: communication with timing variation, extended bit duration 51
5.5.1.3.1 Test execution 51
5.5.1.3.2 Initial conditions 52
5.5.1.3.3 Test procedure 52
5.5.1.4 Test case 3: S1 rise and fall time 52
5.5.1.4.1 Test execution 52
5.5.1.4.2 Initial conditions 52
5.5.1.4.3 Test procedure 53
5.5.1.5 Test case 4: measurement of C6 input capacitance 53
5.5.1.5.1 Test execution 53
5.5.1.5.2 Initial conditions 53
5.5.1.5.3 Test procedure 53
5.5.1.5.4 Example for C6 input capacitance test implementation (informative) 53
5.5.1.6 Test case 5: communication with variation in bit duration 54
5.5.1.6.1 Test execution 54
5.5.1.6.2 Initial conditions 54
5.5.1.6.3 Test procedure 54
5.5.2 S2 switching management 54
5.5.2.1 Conformance requirements 54
5.5.2.2 Test case 1: S2 switching management 54
5.5.2.2.1 Test execution 54
5.5.2.2.2 Initial conditions 54
5.5.2.2.3 Test procedure 54
5.5.3 SWP interface states management 55
5.5.3.1 Conformance requirements 55
5.5.3.2 Test case 1: SWP interface states management by the UICC 55
5.5.3.2.1 Test execution 55
5.5.3.2.2 Initial conditions 55

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5.5.3.2.3 Test procedure 55
5.5.3.3 Test case 2: UICC resume - P3 values and delay after transition sequence 55
5.5.3.3.1 Test execution 55
5.5.3.3.2 Initial conditions 55
5.5.3.3.3 Test procedure 56
5.5.4 Power mode states/transitions and Power saving mode 56
5.5.4.1 Conformance requirements 56
5.5.4.2 Test case 1: power states in low power mode (ACT_POWER_MODE) 57
5.5.4.2.1 Test execution 57
5.5.4.2.2 Initial conditions 57
5.5.4.2.3 Test procedure 57
5.5.4.3 Test case 2: power states in low power mode (non-ACT) 58
5.5.4.3.1 Test execution 58
5.5.4.3.2 Initial conditions 58
5.5.4.3.3 Test procedure 58
5.5.4.4 Test case 3: power states in full power mode, without ETSI TS 102 221 58
5.5.4.4.1 Test execution 58
5.5.4.4.2 Initial conditions 58
5.5.4.4.3 Test procedure 58
5.5.4.5 Test case 4: power saving mode with ETSI TS 102 221 interface - restart ETSI TS 102 221 interface first 58
5.5.4.5.1 Test execution 58
5.5.4.5.2 Initial conditions 59
5.5.4.5.3 Test procedure 59
5.5.4.6 Test case 5: power saving mode with ETSI TS 102 221 interface - restart ETSI TS 102 613 interface first 59
5.5.4.6.1 Test execution 59
5.5.4.6.2 Initial conditions 60
5.5.4.6.3 Test procedure 60
5.5.4.7 Test case 6: power saving mode with ETSI TS 102 600 interface - restart ETSI TS 102 600 interface first 60
5.5.4.7.1 Test execution 60
5.5.4.7.2 Initial conditions 60
5.5.4.7.3 Test procedure 60
5.5.4.8 Test case 7: power saving mode with ETSI TS 102 600 interface - restart ETSI TS 102 613 interface first 60
5.5.4.8.1 Test execution 60
5.5.4.8.2 Initial conditions 61
5.5.4.8.3 Test procedure 61
5.5.4.9 Void 61
5.5.4.10 Test case 9: power saving mode in SUSPENDED, with ETSI TS 102 221 interface restarted first 61
5.5.4.10.1 Test execution 61
5.5.4.10.2 Initial conditions 61
5.5.4.10.3 Test procedure 61
5.5.4.11 Test case 10: power saving mode in SUSPENDED, with ETSI TS 102 221 interface restarted after ETSI TS 102 613 interface 62
5.5.4.11.1 Test execution 62
5.5.4.11.2 Initial conditions 62
5.5.4.11.3 Test procedure 62
5.6 Data link layer 62
5.6.1 Overview 62
5.6.2 Medium Access Control (MAC) layer 62
5.6.2.1 Bit order 62
5.6.2.1.1 Conformance requirements 62
5.6.2.1.2 Void 63
5.6.2.2 Structure 63
5.6.2.2.1 Conformance requirements 63
5.6.2.2.2 Test case 1: interpretation of incorrectly formed frames - ACT LLC 63
5.6.2.2.3 Test case 2: interpretation of incorrectly formed frames - SHDLC RSET frames 63
5.6.2.2.4 Test case 3: interpretation of incorrectly formed frames - SHDLC I-frames 64
5.6.2.2.5 Test case 4: communication with frames - idle bits and wakeup sequence 64
5.6.2.3 Bit stuffing 65

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5.6.2.3.1 Conformance requirements....65
5.6.2.3.2 Test case 1: behaviour of UICC with bit stuffing in frame....65
5.6.2.4 Error detection....66
5.6.2.4.1 Conformance requirements....66
5.6.2.4.2 Test case 1: RSET with CRC error....66
5.6.3 Supported LLC layers....66
5.6.3.1 Supported LLC layers....66
5.6.3.1.1 Conformance requirements....66
5.6.3.1.2 Test case 1: support of ACT LLC and ACT LPDU structure....66
5.6.3.1.3 Test case 2: support of SHDLC LLC and SHDLC LPDU structure....67
5.6.3.2 Interworking of the LLC layers....67
5.6.3.2.1 Conformance requirements....67
5.6.3.2.2 Test case 1: error handling of ACT LLC on reception of corrupted frame, after SWIO activation....68
5.6.3.2.3 Test case 2: ignore ACT LLC frame reception after the SHDLC link establishment....68
5.6.3.2.4 Test case 3: ignore ACT LLC frame reception in CLT session....68
5.6.3.2.5 Test case 4: CLT session during SHDLC communication....69
5.6.3.2.6 Test case 5: closing condition of CLT session whereas SHDLC link has been established before CLT session....69
5.6.3.2.7 Test case 6: closing condition of CLT session whereas SHDLC link has not been established before CLT session....70
5.6.3.2.8 Test case 7: interpretation of corrupted frames - single SHDLC frame....70
5.6.3.2.9 Void....70
5.6.3.2.10 Test case 9: interpretation of corrupted frames - CLT frames....70
5.6.3.2.11 Test case 10: first non-ACT frame sent by CLF - initial interface activation....71
5.6.3.2.12 Test case 11: first non-ACT frame sent by CLF - subsequent interface activation....71
5.6.4 ACT LLC definition....72
5.6.4.1 ACT LLC definition....72
5.6.4.1.1 Conformance requirements....72
5.6.4.1.2 Test case 1: structure of ACT LPDU - full power mode....72
5.6.4.1.3 Test case 2: structure of ACT LPDU - low power mode....72
5.6.4.1.4 Test case 3: behaviour of UICC on reception of ACT frames - values of INF bit....73
5.6.4.1.5 Test case 4: RFU values in ACT_INFORMATION field....73
5.6.4.1.6 Test case 5: extended bit durations as per ACT_INFORMATION field....74
5.6.4.1.7 Test case 6: RFU values in ACT_INFORMATION field....74
5.6.4.2 SYNC_ID verification process....75
5.6.4.2.1 Conformance requirements....75
5.7 SHDLC LLC definition....75
5.7.1 SHDLC overview....75
5.7.1.1 Conformance requirements....75
5.7.1.2 Test Case 1: data passed up to the next layer....75
5.7.1.2.1 Test execution....75
5.7.1.2.2 Initial conditions....75
5.7.1.2.3 Test procedure....75
5.7.1.3 Test Case 2: error management, UICC sending I-Frame....76
5.7.1.3.1 Test execution....76
5.7.1.3.2 Initial Conditions....76
5.7.1.3.3 Test procedure....76
5.7.1.4 Test Case 3: error management....76
5.7.1.4.1 Test execution....76
5.7.1.4.2 Initial Conditions....76
5.7.1.4.3 Test procedure....76
5.7.2 Endpoints....76
5.7.2.1 Conformance requirements....76
5.7.3 SHDLC frames types....76
5.7.3.1 Conformance requirements....76
5.7.4 Control Field....77
5.7.4.1 Conformance requirements....77
5.7.4.2 I-Frames coding....77
5.7.4.2.1 Conformance requirements....77
5.7.4.3 S-Frames coding....77
5.7.4.3.1 Conformance requirements....77

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Full standard:
https://standards.iteh.ai/catalog/standards/sist/40b86961-5782-482f-a84f-1bb6e6b6c60b/etsi-ts-102-694-2-v10.3.0-2015-03

5.7.4.4 U-Frames coding 77
5.7.4.4.1 Conformance requirements 77
5.7.5 Changing sliding window size and endpoint capabilities 77
5.7.5.1 Conformance requirements 77
5.7.5.2 RSET frame payload 77
5.7.5.2.1 Conformance requirements 77
5.7.5.3 UA frame payload 77
5.7.5.3.1 Conformance requirements 77
5.7.5.3.2 Void 78
5.7.6 SHDLC context 78
5.7.6.1 Conformance requirements 78
5.7.6.2 Constants 78
5.7.6.2.1 Conformance requirements 78
5.7.6.3 Variables 78
5.7.6.3.1 Conformance requirements 78
5.7.6.4 Initial Reset state 78
5.7.6.4.1 Conformance requirements 78
5.7.6.4.2 Test case 1: initial state at link reset - reset by the UICC 78
5.7.6.4.3 Test case 2: initial state at link reset - reset by the terminal simulator 79
5.7.7 SHDLC sequence of frames 79
5.7.7.1 Conformance requirements 79
5.7.7.2 Nomenclature 80
5.7.7.2.1 Conformance requirements 80
5.7.7.3 Link establishment with default sliding window size 80
5.7.7.3.1 Conformance requirements 80
5.7.7.3.2 Test Case 1: link establishment by the UICC 80
5.7.7.3.3 Test Case 2: link establishment by the terminal simulator 81
5.7.7.3.4 Test case 3: discard frames before initialization 81
5.7.7.3.5 Test case 4: connection time - reset by UICC 82
5.7.7.3.6 Test case 5: connection time - reset by terminal simulator 82
5.7.7.3.7 Test case 6: UICC discards I-frames and S-frames during link establishment 83
5.7.7.3.8 Test case 7: requesting unsupported window size - link establishment by terminal simulator 83
5.7.7.3.9 Test Case 8: requesting unsupported SREJ support - link establishment by terminal simulator 83
5.7.7.3.10 Test Case 9: requesting unsupported window size and SREJ support - link establishment by terminal simulator 84
5.7.7.3.11 Test Case 10: forcing lower window size - link establishment by the UICC 84
5.7.7.3.12 Test Case 11: forcing SREJ not used - link establishment by the UICC 85
5.7.7.3.13 Test Case 12: forcing lower window size and SREJ not used - link establishment by the UICC 85
5.7.7.3.14 Test case 13: discard buffered frames on link re-establishment 85
5.7.7.4 Link establishment with custom sliding window size 86
5.7.7.4.1 Conformance requirements 86
5.7.7.5 Data flow 86
5.7.7.5.1 Conformance requirements 86
5.7.7.5.2 Test case 1: I-frame transmission 86
5.7.7.5.3 Test case 2: I-frame reception - single I-Frame reception 87
5.7.7.5.4 Test case 3: I-frame reception - multiple I-Frame reception 87
5.7.7.5.5 Test case 4: piggybacking 88
5.7.7.6 Reject (go N back) 88
5.7.7.6.1 Conformance requirements 88
5.7.7.6.2 Test case 1: REJ transmission 89
5.7.7.6.3 Test case 2: REJ transmission - multiple I-frames received 89
5.7.7.6.4 Test case 3: REJ reception 90
5.7.7.7 Last Frame Loss 90
5.7.7.7.1 Conformance requirements 90
5.7.7.7.2 Test Case 1: retransmission of a single frame 91
5.7.7.7.3 Test Case 2: retransmission of multiple frames 91
5.7.7.8 Receive and not ready 91
5.7.7.8.1 Conformance requirements 91
5.7.7.8.2 Test case 1: RNR reception 92
5.7.7.8.3 Test case 2: Empty I-frame transmission 92
5.7.7.9 Selective reject 93

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https://standards.iteh.ai/catalog/standards/sist/0d8696f2-5782-4824-4848-d0e6e6e6e6db/etsi-ts-102-694-2-v10.3.0-2015-03

5.7.7.9.1 Conformance requirements....93
5.7.7.9.2 Test case 1: SREJ transmission....93
5.7.7.9.3 Test case 2: SREJ transmission - multiple I-frames received....94
5.7.7.9.4 Test case 3: SREJ reception....94
5.7.7.9.5 Void....94
5.7.8 Implementation....94
5.7.8.1 Conformance requirements....94
5.7.8.2 Information Frame emission....94
5.7.8.2.1 Conformance requirements....94
5.7.8.3 Information Frame reception....95
5.7.8.3.1 Conformance requirements....95
5.7.8.4 Reception Ready Frame reception....95
5.7.8.4.1 Conformance requirements....95
5.7.8.5 Reject Frame reception....95
5.7.8.5.1 Conformance requirements....95
5.7.8.6 Selective Reject Frame reception....95
5.7.8.6.1 Conformance requirements....95
5.7.8.7 Acknowledge timeout....95
5.7.8.7.1 Conformance requirements....95
5.7.8.8 Guarding/transmit timeout....95
5.7.8.8.1 Conformance requirements....95
5.8 CLT LLC definition....95
5.8.1 System Assumptions....95
5.8.2 Overview....95
5.8.3 Supported RF protocols....96
5.8.3.1 Conformance requirements....96
5.8.4 CLT Frame Format....96
5.8.4.1 Conformance requirements....96
5.8.4.2 Test case 1: Padding of CLT PAYLOAD in Type A aligned structure....96
5.8.4.2.1 Test execution....96
5.8.4.2.2 Initial conditions....96
5.8.4.2.3 Test procedure....96
5.8.5 CLT Command Set....97
5.8.5.1 Conformance requirements....97
5.8.5.2 Test case 1: CLT commands, ISO/IEC 14443-3 Type A....97
5.8.5.2.1 Test execution....97
5.8.5.2.2 Initial conditions....97
5.8.5.2.3 Test procedure....97
5.8.5.3 Test case 2: CLT commands, ISO/IEC 18092....98
5.8.5.3.1 Test execution....98
5.8.5.3.2 Initial conditions....98
5.8.5.3.3 Test procedure....98
5.8.6 CLT Frame Interpretation....99
5.8.6.1 CLT frames with Type A aligned DATA_FIELD....99
5.8.6.1.1 Conformance requirements....99
5.8.6.2 Handling of DATA_FIELD by the CLF....99
5.8.6.2.1 Conformance requirements....99
5.8.6.3 Handling of ADMIN_FIELD....99
5.8.6.3.1 CL_PROTO_INF(A)....99
5.8.6.3.2 CL_PROTO_INF(F)....100
5.8.6.3.3 CL_GOTO_INIT and CL_GOTO_HALT....102
5.8.7 CLT Protocol Rules....102
5.8.7.1 Rules for the CLF....102
5.8.7.2 Rules for the UICC....102
5.8.7.2.1 Conformance requirements....102
5.9 Timing and performance....102

Annex A (informative): State diagrams....103

A.1 SDL symbols definition....103

A.2 Initial SWP interface activation....104

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A.3 SHDLC operation.....106

Annex B (informative): Bibliography.....114

Annex C (informative): Core specification version information.....115

Annex D (informative): Change history.....116

History.....118

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Foreword

This Technical Specification (TS) has been produced by ETSI Technical Committee Smart Card Platform (SCP).

The contents of the present document are subject to continuing work within TC SCP and may change following formal TC SCP approval. If TC SCP modifies the contents of the present document, it will then be republished by ETSI with an identifying change of release date and an increase in version number as follows:

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y the second digit is incremented for all changes of substance, i.e. technical enhancements, corrections, updates, etc.

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The present document is part 2 of a multi-part deliverable covering the Test specification for the Single Wire Protocol (SWP) interface, as identified below:

Part 1: "Terminal features";

Part 2: "UICC features".

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Modal verbs terminology

In the present document "**shall**", "**shall not**", "**should**", "**should not**", "**may**", "**need not**", "**will**", "**will not**", "**can**" and "**cannot**" are to be interpreted as described in clause 3.2 of the ETSI Drafting Rules (Verbal forms for the expression of provisions).

"**must**" and "**must not**" are **NOT** allowed in ETSI deliverables except when used in direct citation.

Introduction

The present document defines test cases for the UICC relating to Single Wire Protocol (SWP). SWP is the communication interface between the UICC and a contactless frontend (CLF) as specified in ETSI TS 102 613 [1].

The aim of the present document is to ensure interoperability between the terminal and the UICC independently of the respective manufacturer, card issuer or operator.

1 Scope

The present document covers the minimum characteristics which are considered necessary for the UICC in order to provide compliance to ETSI TS 102 613 [1].

The present document specifies the test cases for:

- the physical layer of the interface CLF - UICC;
- the electrical interface of the UICC;
- the initial communication establishment CLF - UICC;
- the data link layer.

Test cases for the terminal relating to ETSI TS 102 613 [1] and test cases for the host controller interface (HCI) covering both terminal and UICC are out of scope of the present document.

2 References

2.1 Normative references

References are either specific (identified by date of publication and/or edition number or version number) or non-specific. For specific references, only the cited version applies. For non-specific references, the latest version of the reference document (including any amendments) applies.

- In the case of a reference to a TC SCP document, a non specific reference implicitly refers to the latest version of that document in the same Release as the present document.

Referenced documents which are not found to be publicly available in the expected location might be found at http://docbox.etsi.org/Reference.

NOTE: While any hyperlinks included in this clause were valid at the time of publication, ETSI cannot guarantee their long term validity.

The following referenced documents are necessary for the application of the present document.

[1] ETSI TS 102 613: "Smart Cards; UICC - Contactless Front-end (CLF) Interface; Part 1: Physical and data link layer characteristics".

[2] ETSI TS 102 221: "Smart Cards; UICC-Terminal interface; Physical and logical characteristics".

[3] ETSI TS 102 600: "Smart Cards; UICC-Terminal interface; Characteristics of the USB interface".

[4] ETSI TS 102 622: "Smart Cards; UICC - Contactless Front-end (CLF) Interface; Host Controller Interface (HCI)".

[5] ISO/IEC 9646-7: "Information technology - Open Systems Interconnection - Conformance testing methodology and framework - Part 7: Implementation Conformance Statements".

[6] ISO/IEC 14443-3: "Identification cards - Contactless integrated circuit cards - Proximity cards - Part 3: Initialization and anticollision".

[7] Void.

[8] ISO/IEC 18092: "Information technology - Telecommunications and information exchange between systems - Near Field Communication - Interface and Protocol (NFCIP-1)".

[9] ISO/IEC 13239: "Information technology - Telecommunications and information exchange between systems - High-level data link control (HDLC) procedures".

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2.2 Informative references

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The following referenced documents are not necessary for the application of the present document but they assist the user with regard to a particular subject area.

Not applicable.

3 Definitions, symbols and abbreviations

3.1 Definitions

For the purposes of the present document, the terms and definitions given in ETSI TS 102 613 [1] and the following apply:

corrupted frame: SWP frame which is well-formed with respect to the MAC layer, with the exception that the CRC16 in the frame does not match with the CRC16 result calculated over the payload

NOTE: This frame has at least 1 byte payload. Used by the TE to represent the situation where the DUT receives a corrupted frame (unless otherwise specified).

non-occurrence RQ: RQ which has been extracted from ETSI TS 102 613 [1], but which indicates a situation which should never occur

NOTE: The consequence is that such RQs cannot be explicitly tested.

nomenclature used for tests involving SHDLC LLC:

For SHDLC link establishment, following definitions apply:

- Terminal simulator transmits RSET:
  - RSET(): RSET frame without payload.
  - RSET(Ws=w): RSET frame with one byte payload.
  - RSET(Ws=w, SREJ=S): RSET frame with two bytes payload. For the endpoint capabilities byte, SREJ=0 represents the value 0x00, SREJ=1 represents the value 0x01.
- UICC transmits RSET:
  - RSET: RSET frame with any valid payload.
  - RSET(): RSET frame without payload.
  - RSET(Ws=w): RSET frame with one byte payload.
  - RSET(Ws=w, SREJ=S): RSET frame with two bytes payload. For the endpoint capabilities byte, SREJ=0 represents the value 0x00, SREJ=1 represents the value 0x01.

For every calculation on NS0_T, NS0_S or NR in the test procedures use modulo 8.

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